**Power LDMOS transistor** 

Rev. 3 — 16 February 2012

**Product data sheet** 

### 1. Product profile

#### 1.1 General description

160 W LDMOS power transistor for base station applications at frequencies from 920 MHz to 960 MHz.

#### Table 1. Typical performance

Typical RF performance at  $T_{case} = 25 \$ °C in a common source class-AB production test circuit.

Test signal	f	I <sub>Dq</sub>	$V_{\text{DS}}$	P <sub>L(AV)</sub>	Gp	$\eta_D$	ACPR
	(MHz)	(mA)	(V)	(W)	(dB)	(%)	(dBc)
2-carrier W-CDMA	920 to 960	1100	30	35	19.7	29	-38 <mark>[1]</mark>

 Test signal: 3GPP; test model 1; 64 DPCH; PAR = 7.5 dB at 0.01 % probability on CCDF per carrier. Carrier spacing 5 MHz.

#### **1.2 Features and benefits**

- Excellent ruggedness
- High efficiency
- Low R<sub>th</sub> providing excellent thermal stability
- Designed for broadband operation (920 MHz to 960 MHz)
- Lower output capacitance for improved performance in Doherty applications
- Designed for low memory effects providing excellent pre-distortability
- Internally matched for ease of use
- Integrated ESD protection
- Compliant to Directive 2002/95/EC, regarding Restriction of Hazardous Substances (RoHS)

#### **1.3 Applications**

 RF power amplifiers for W-CDMA base stations and multi carrier applications in the 920 MHz to 960 MHz frequency range



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## 2. Pinning information

Pin	Description	Simplified outline	Graphic symbol
BLF8G10	0L-160 (SOT502A)		
1	drain		
2	gate		1 لـــا
3	source		2
			3 sym112
BLF8G10	DLS-160 (SOT502B)		
1	drain		
2	gate		۲ لــــا
3	source		
			3
			sym112

## 3. Ordering information

Table 3. Ordering information					
Type number Package					
	Name	Description	Version		
BLF8G10L-160	-	flanged LDMOST ceramic package; 2 mounting holes; 2 leads	SOT502A		
BLF8G10LS-160	-	earless flanged LDMOST ceramic package; 2 leads	SOT502B		

## 4. Limiting values

#### Table 4. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Min	Max	Unit
V <sub>DS</sub>	drain-source voltage		-	65	V
$V_{GS}$	gate-source voltage		-0.5	+13	V
T <sub>stg</sub>	storage temperature		-65	+150	°C
Tj	junction temperature		-	200	°C

## 5. Thermal characteristics

Table 5.	Thermal characteristics			
Symbol	Parameter	Conditions	Тур	Unit
R <sub>th(j-c)</sub>	thermal resistance from junction to case	$T_{case} = 80 \ ^{\circ}C; P_{L} = 35 \ W;$ $V_{DS} = 30 \ V; I_{Dq} = 1100 \ mA$	0.50	K/W

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### 6. Characteristics

<b>Table 6.</b> $T_j = 25 \ ^{\circ}C$	Characteristics Cunless otherwise specified.					
Symbol	Parameter	Conditions	Min	Тур	Мах	Unit
$V_{(BR)DSS}$	drain-source breakdown voltage	$V_{GS}$ = 0 V; $I_D$ = 2.2 mA	65	-	-	V
V <sub>GS(th)</sub>	gate-source threshold voltage	$V_{DS}$ = 10 V; $I_{D}$ = 220 mA	1.5	2.0	2.3	V
I <sub>DSS</sub>	drain leakage current	$V_{GS} = 0 \text{ V}; V_{DS} = 28 \text{ V}$	-	-	5	μΑ
I <sub>DSX</sub>	drain cut-off current	$\label{eq:VGS} \begin{array}{l} V_{GS} = V_{GS(th)} + 3.75 \; V; \\ V_{DS} = 10 \; V \end{array}$	-	37.0	-	A
I <sub>GSS</sub>	gate leakage current	$V_{GS}$ = 11 V; $V_{DS}$ = 0 V	-	-	0.5	μA
9 <sub>fs</sub>	forward transconductance	$V_{DS} = 10 \text{ V}; \text{ I}_{D} = 7.7 \text{ A}$	-	14.6	-	S
R <sub>DS(on)</sub>	drain-source on-state resistance	$V_{GS} = V_{GS(th)} + 3.75 V;$ $I_D = 7.7 A$	-	86	-	mΩ

## 7. Test information

#### Table 7. Functional test information

Test signal: 2-carrier W-CDMA; PAR = 7.5 dB at 0.01 % probability on the CCDF; 3GPP test model 1; 64 DPCH;  $f_1$  = 920 MHz;  $f_2$  = 925 MHz;  $f_3$  = 955 MHz;  $f_4$  = 960 MHz; RF performance at  $V_{DS}$  = 30 V;  $I_{Dq}$  = 1100 mA;  $T_{case}$  = 25 °C; unless otherwise specified; in a class-AB production test circuit.

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Gp	power gain	$P_{L(AV)} = 35 \text{ W}$	19	19.7	-	dB
RL <sub>in</sub>	input return loss	$P_{L(AV)} = 35 \text{ W}$	-	-15	-10	dB
$\eta_D$	drain efficiency	$P_{L(AV)} = 35 \text{ W}$	27	29	-	%
ACPR	adjacent channel power ratio	$P_{L(AV)} = 35 \text{ W}$	-	-38	-34	dBc

#### 7.1 Ruggedness in class-AB operation

The BLF8G10L-160 and BLF8G10LS-160 are capable of withstanding a load mismatch corresponding to VSWR = 10 : 1 through all phases under the following conditions:  $V_{DS} = 30 \text{ V}; I_{Dq} = 1100 \text{ mA}; P_L = 130 \text{ W} (CW); f = 920 \text{ MHz} to 960 \text{ MHz}.$ 

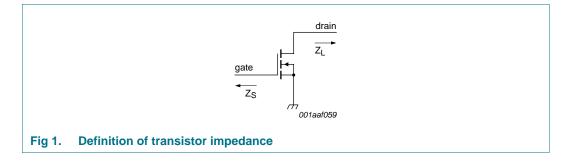
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### 7.2 Impedance information

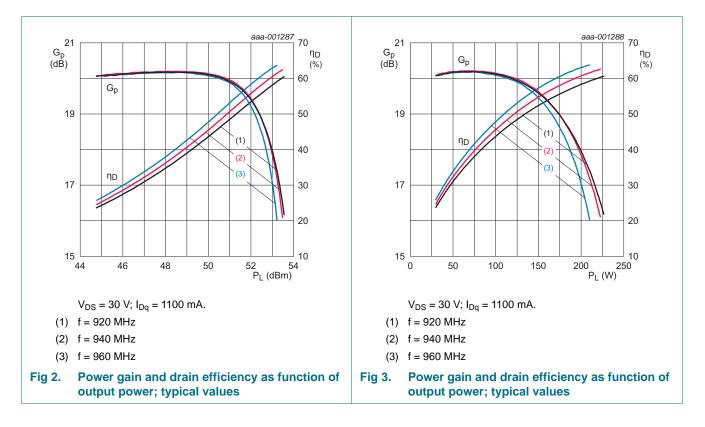
Table 8.Typical impedance information $I_{Dg} = 1100 \text{ mA}$ ; main transistor  $V_{DS} = 30 \text{ V}$ .

Zo and Z.	defined in	Figure	1
$z_S and z_L$	ucinicu in	riguie	· ·

f	Z <sub>S</sub>	ZL
(MHz)	(Ω)	(Ω)
925	4.0 - j3.8	1.7 – j2.5
942	4.4 - j4.2	1.5 – j2.2
960	4.6 – j4.1	1.4 – j2.3



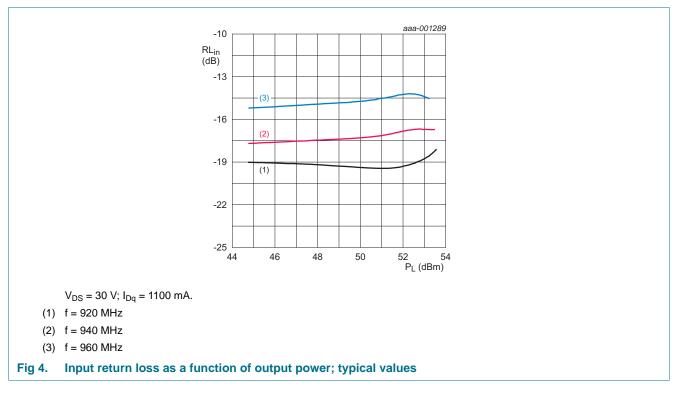
### 7.3 CW pulse



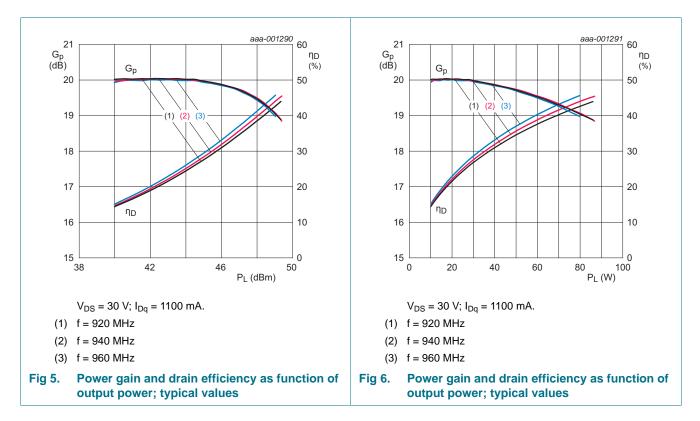
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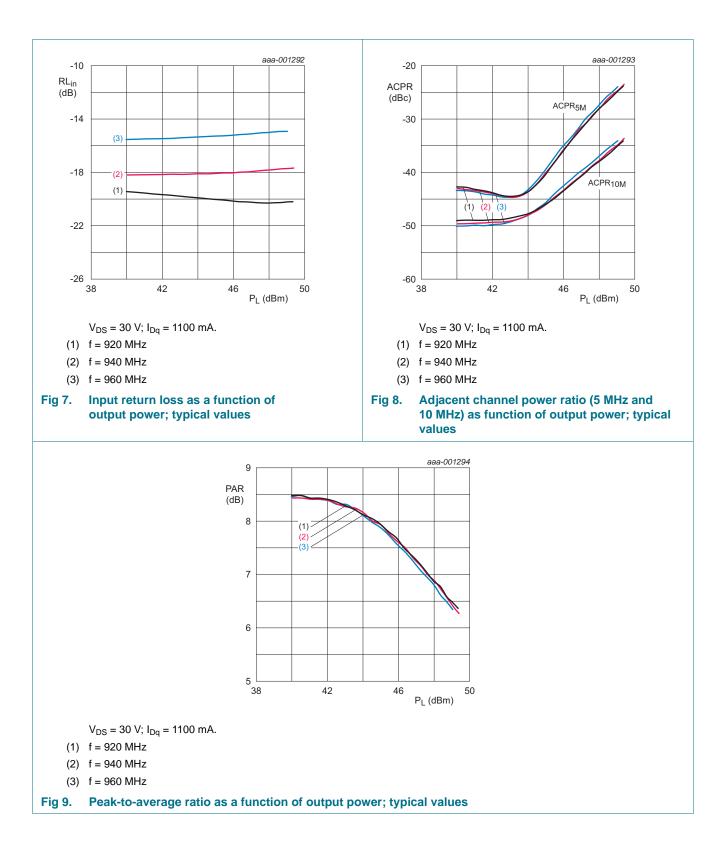




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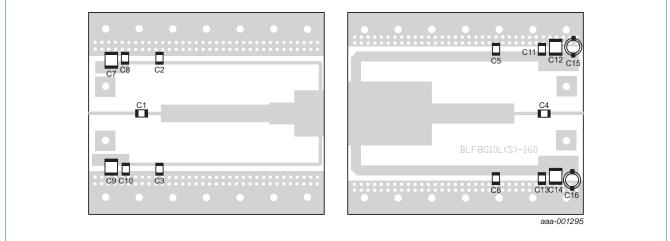
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BLF8G10L-160\_8G10LS-160

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#### 7.5 Circuit



Printed-Circuit Board (PCB): Rogers RO4350;  $\varepsilon_r$  = 3.5 F/m; thickness = 0.762 mm; thickness copper plating = 35  $\mu$ m. The vias can be used as a reference to place components.

The above layout shows the test circuit used to measure the devices in production. A more appropriate application demonstration for specific customer needs can be provided.

See <u>Table 9</u> for list of components.

#### Fig 10. Component layout

## Table 9.List of componentsSee Figure 10 for component layout.

Component	Description	Value	Remarks
C1, C2, C3, C4, C5, C6	multilayer ceramic chip capacitor	82 pF	ATC 800B
C7, C9, C12, C14	multilayer ceramic chip capacitor	10 μF	Murata
C8, C10, C11, C13	multilayer ceramic chip capacitor	1 μF	Murata
C15, C16	electrolytic capacitor	470 μF; 63 V	

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### 8. Package outline

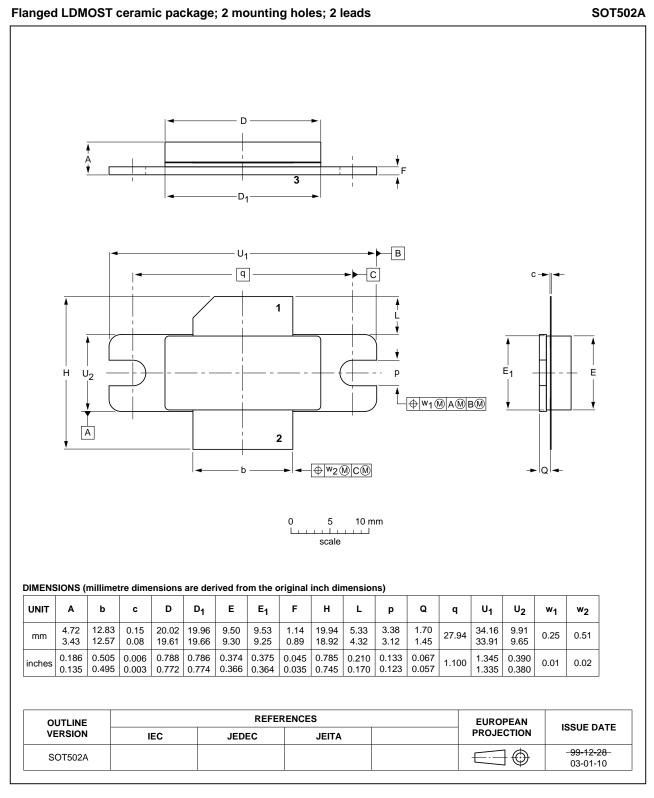
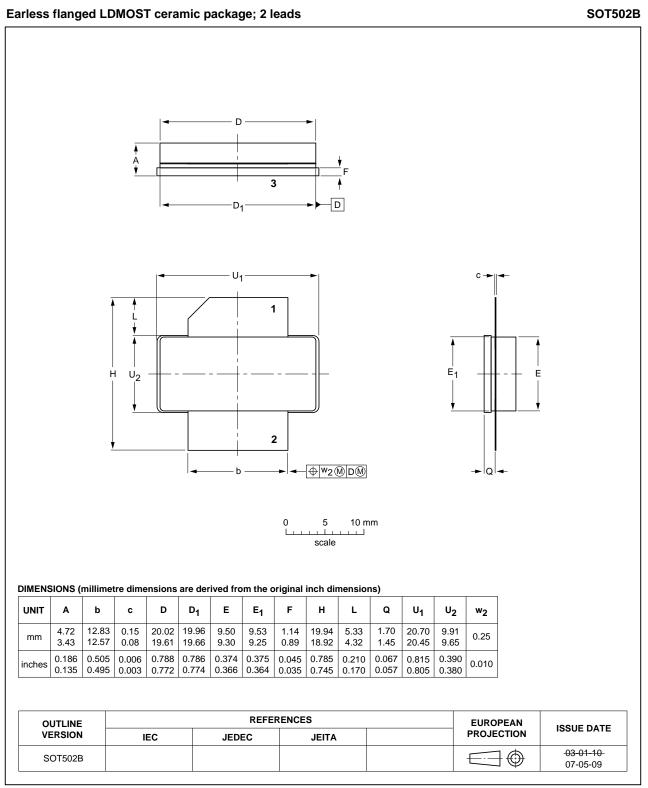


Fig 11. Package outline SOT502A

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## Fig 12. Package outline SOT502B

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## 9. Abbreviations

Table 10.	Abbreviations
Acronym	Description
3GPP	Third Generation Partnership Project
CCDF	Complementary Cumulative Distribution Function
CW	Continuous Wave
DPCH	Dedicated Physical CHannel
ESD	ElectroStatic Discharge
LDMOS	Laterally Diffused Metal Oxide Semiconductor
LDMOST	Laterally Diffused Metal Oxide Semiconductor Transistor
PAR	Peak-to-Average power Ratio
RF	Radio Frequency
VSWR	Voltage Standing Wave Ratio
W-CDMA	Wideband Code Division Multiple Access

## **10. Revision history**

Table 11.         Revision history				
Document ID	Release date	Data sheet status	Change notice	Supersedes
BLF8G10L-160_8G10LS-160 v.3	20120216	Product data sheet		BLF8G10L-160_8G10LS-160 v.2
Modifications:	<ul> <li>The statu</li> </ul>	us of this data sheet has	been changed to I	Product data sheet
	• Table 6 c	on page 3: I <sub>D</sub> value chan	ged to 2.2 mA at c	onditions of $V_{(BR)DSS}$
	• Table 8 c	on page 4: values rounde	ed off to one decim	al place
BLF8G10L-160_8G10LS-160 v.2	20111121	Preliminary data sheet		BLF8G10L-160_8G10LS-160 v.1
BLF8G10L-160_8G10LS-160 v.1	20110519	Objective data sheet	-	-

## **11. Legal information**

#### 11.1 Data sheet status

Document status[1][2]	Product status <sup>[3]</sup>	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

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